

ABSTRACT

To attain an object of providing an insert for
5 holding wide-ranging kinds of area array type electronic
components and realizing certain connection between
external terminals of an area array type electronic
component and connection terminals of a socket, and an
electronic component testing apparatus and an electronic
10 component testing method using the same, a thin plate 163
for supporting an IC device 2 is positioned between an
external terminal face 23 of the IC device 2 and a
connection terminal face 42 of a socket 40, and a
thickness of the thin plate 163 is made to be
15 approximately equal to or less than a distance between a
tip portion of the external terminals 22 and the external
terminal face 23.